

Tailor Your Company's Training – Pick & Choose Topics Reliability, Shock & Vibration, Physics of Failure (Mechanical & Electronic) & ESD Training

Courses use DfRSoftware which is optional but helpful.

PART 1: BASIC METHODS IN RELIABILITY & QUALITY

1. Reliability & Quality in Today's Marketplace

- A Practical Approach to Reliability Implementation
- Reliability Growth and ROI
- Reliability as a Differentiator
- The Main Components of a DfRQ Company Program

2. The Phase Approach

- Idea, Evaluate, Development, Transition, Production
- Understanding Each Gate - The Tools for your Program
- Piecing it Together - A Value Added Reliability Program

3. Basic Reliability Mathematics (Using DfRSoft Tools)

- MTBF/Failure Rate Basics
- Failure Rate Conversion (FITs, FMH, MTBF, PPM, AFR, %Failure)
- System Reliability Analysis & Block Diagrams (Series, Parallel, Redundancy for K of N, Active/Standbys)
- Allocation (equal apportionment and by complexity)
- Reliability Predictions (Parts Count, Detailed Stress, Telcordia, Mil Std 217...)
- Advanced Reliability Mathematics (See Module 8)

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4a. Basic Quality Test Engineering

(Using DfRSoft Tools)

- Cpk, Yield, Normal/Lognormal, & Six Sigma Analysis
- SPC Charts
- Visual Inspection/Design Release

4b. Lot Sampling detail in lot sampling

4c. Design of Experiment with Multiple Regression

4d. Stack Up & Monte Carlo Analysis Methods

- Stack up
- Worst case stack up analysis
- Stack up Example
- Monte Carlo Methods for stack up

PART 2: DEMONSTRATING & ANALYZING RELIABILITY

CONCEPT PHASE – (IDEA) PHASE

5. How to Develop a Reliability Program Planning

- Method of Top Down FMEA
- Top Down FMEA for Program Planning

- Team Approach
- Design Controls & Recommended Actions
- How to Make a Program Plan with Top Down Example

5a Bottoms Up Design FMEA

- Key to a Good DFMEA
- Most Efficient DFMEA
- DFMEA Environmental Approach (Component sensitivity)
- Examples

DESIGN PHASE – (EVALUATION) – PHASE

6. Design Assessment Reliability Testing & Reliability Growth (DART - HALT)

(DfRSoft Tools)

- Finding Failure Modes – Test to Fail Not to Pass
- Accelerated Reliability Growth
- Chi-Squared Accelerated Reliability Growth
- Test Design by Failure Modes
- HALT Introduction & Concept, Detailed Test Procedure, Max limits, Failure Judgment
- HALT Helpful Information: Table Assessment, Meetings, Check list, Guidelines,
- HALT Table Vibration Assessment,
- *ED vs. HALT (See Shock & Vibration Module 14)*
- *HASS (see Screening Module 11)*

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7. Design for Reliability Methods

- Reliability Design Safety Margin – Load-Stress Reliability Interference Assessment
- Design Mechanical Safety Factors
- Electrical Derating
- *Assessing Potential Thermal Issues (moved to 19)*
- *Engelmaier IPC Solder Joint Life Model, BGAs (Less time) (moved to 19)*

DEVELOP - PHASE

8. Advanced Reliability Mathematics

(Using DfRSoft Tools)

- Time Dependent Failure Rate
- Main Distribution of the Bathtub Curve, Weibull, Exponential, and Lognormal
- Key Reliability Functions (CDF, PDF, Hazard Rate)
- Introduction to Reliability Life Data Plotting Using Software
- *Mixed Modes Analysis (see Module 12)*
- How the Weibull & Lognormal Distributions Relates to Physics of Failure Aging Laws (Beta significance)

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9. Accelerated Life Models & Environmental Profiling

- Acceleration Factors & Models (Temperature-Arrhenius, Peck Temperature-Humidity, Coffin-Manson Temperature Cycle, Modified Frequency Temperature Cycle, Vibration Accelerated Models, General Power Law Model)
- Chi-squared confidence method for accelerated testing

- Environmental Profiling (model for environments with varying stress profiles)
- Homework with Solutions*

10. Design Maturity Chi-Squared Demonstration Testing (Using DfRSoft Tools)

- Will Your Product Meet its Reliability Objective?
- Design Maturity Test Plans and Flow
- Types of Confidence
- Testing for a Reliability Failure Rate Objective
- Statistically Significant Confidence Accelerated Test Plans
- Importance of Device Hours
- Pros and Cons of Device Hours
- Device Hours – Multiple Test Uses

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RELIABILITY MANUFACTURING & SUPPORT PHASE

11. Reliability Monitoring and Screening

- Screening vs. Monitoring
- Common Screens and Monitoring Tests
- HASS Screening

12. Field Returns and Device Hours (DfRSoft Tools)

- AFR – Most common company metric
- Field Return– Raw Data Analysis
- Device Hours – Multiple Test Uses and Field Returns
- Field Return– Weibull Analysis, Mixed FM, (two populations)
- Mixed Modes Analysis (field returns, two or more populations)

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13. Availability & Sparing (DfRSoft Tools) (Less time)

- Exponential Distribution with Binomial Confidence (other methods - Weibull)
- Why availability can be a better number for customers than MTBF

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PART 3 SPECIAL TOPICS TAYLORED TO THE CLASS' NEEDS

14. Understanding Shock & Vibration and Related Tests

Shock

- Overview of Shock & Vibration
- What is a G, g, Grms, G-force
- Shock testing; electrodynamic (ED), drop shock
- Shock Equipment; ED, Air Shock, Incline, Drop Shock, Tower Test
- Common types of shock pulses
- How does 1G free fall create large G shocks?
- Physics of drop shock; different pulse shapes, rebound effect
- Drop height for different masses; PE method
- Calculating drop height for different pulse shapes
- Shock Fatigue Testing
- Shock Response Spectrum (SRS); pyroshock, earthquake, seismic shock

- o Shock & package test references; Mil-STD, ASTM, ISTA

Sine Vibration

- o Basics of sine testing using the ED shaker, test fixtures
- o ED Vibration Lab Set-up - Similar to Car Stereo
- o Fixtures & ED Shaker Test Limits
- o Sine wave basics; phase effect, track & dwell, resonance & Q
- o Sine wave math – amplitude, velocity, acceleration
- o Transmissibility, Q, two graphical methods for Q
- o Harmonic oscillator physics; natural & forcing frequency, academic & real world Q
- o Details of damping, transmissibility Q, resonance
- o Sine amplitude equations with Q factor
- o Sweep Rate – Octaves, consequences of too fast a sweep rate
- o Dwell sine testing
- o Sine Fatigue Life S-N Curves, how the b factor effects the acceleration model
- o Accelerated testing using S-N curve information or historic information
- o High G level testing, G, RPM

Random vibration testing

- o Why random
- o Understanding random frequency & time domain
- o Fourier Transform – White Noise
- o Why sine & random are hard to compare
- o ED vs. repetitive shock
- o Some PSD Specs.
- o Calculating Grms from PSD spectrum; hand and complex calculation using DfRSoft tool,
- o PSD slope (dB/Octave)
- o Transportation vibration exposure
- o Random vibration accelerated cyclic testing fatigue life estimation
- o Estimating Q from random vibration data
- o Tri-axial fixturing, X, Y, Z data, tri-axial testing
- o Accelerometers
- o Sine-on-random, Random-on-random

HALT Repetitive Shock Vibration

- o ED vs. HALT
- o HALT Table PSD-frequency Profile

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15. Design Considerations in Shock & Vibration

Isolation & Damping - Designing for Vibration & Shock Suppression

- o Vibration Isolation
- o Shock Isolation/Absorption
- o Packaging guidelines - foam thickness
- o Vibration Absorption/Damping

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16. Mechanical Physics of Failure & Material Selection Stress Considerations

- o *Elastic deformation, yielding (with vibration) and ductile rupture*
(with shock) material considerations

- o **Creep** & cumulative creep fatigue material considerations, viscoelastic creep, creep acceleration factor
 - o **Excessive wear**; friction & lubrication – types of wear, vibration wear, material selection & hardness, wear acceleration factor
 - o **Cyclic Fatigue**: Exact method for damage estimation (derivation using thermodynamic work)
 - o **Miner's approximation** – derivation, why it is an approx., stress concentration
 - o **SN curves** – material selection
 - o Fatigue (SN curves, Basquin's and Coffin-Manson -high and low cyclic fatigue, Loading Types - stress corrections, Fracture Mech. Vibration fatigue, when SN Curves not available)
 - o **PCB fatigue life** - Circuit board component fatigue life model analysis –Steinberg Method (sine and random)
 - o **Thermal cycle** (strain, fatigue, acceleration factors derivations for Coffin-Manson & Modified, Norris-Landzberg
 - o Method of Combining Thermal & Vibration fatigue
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17. Physics of Failure 7 Step Problem Solving

18. Physics of Failure Analysis Tools

- o Digital Microscopy
- o SEM (FE-SEM, EDS)
- o Focused Ion Beam
- o Scanning Auger
- o C-SAM
- o Real Time Radiology, X-Ray Maps, o X-Ray Fluorescence XRF
- o FTIR, Thermal Imaging
- o Functional Electrical Test (Curve Trace)
- o EMI, EMC

19. Electronic & IC Physics of Failure Considerations

- o Thermal Cycle CTE Stress Issues
 - o CTE's Mismatch, Thermal Fatigue
 - o Engelmaier IPC Solder Joint Life Model, BGAs (Less time)
 - o Underfill & Modification to Englemaier model
- o Drop shock & vibration Electronic Failure modes
- o Temperature: Thermally Activated Failure Modes
 - o Top IC Failure Modes due to Heat, Popcorn Cracking, Voiding Delamination
 - o Junction Temperature Issues & Modeling
- o Voltage Issues
 - o ESD and EOS – Dielectric Breakdown
- o Current Density & Fusing of Bond wires and wires
- o Misc PoF Failure Modes
 - o Design Warnings
 - o Electrolytic Caps
 - o Assembly Errors
 - o IC Failure Modes (Latch up, Gate Sinking, Hot Carrier,...)
 - o Solder Failures (non wetting, grain size, leaching, coverage)
 - o Intermetallics - Au Embrittlement, Purple Plague
- o Corrosion (are we covering this?)
 - o Corrosion Requirements
 - o Key Forms of Corrosion (General, Galvanic, stress corrosion, Cl.)

- Moisture & Waterproofing (Conformal Coating, Encapsulation, Super Hydrophobic)
- Dendritic Growth, Ag Migration & Electromigration
- RoHS Lead Free Solder Issues
 - Lead Free Issues: European directive, Pb-Free Failure Modes, SAC Solders
 - PCB Copper Dissolution from reflow - Via issues, PCB CTE Z-direction issues
 - Surface finishes (ENIG, Immersion Silver, Immersion Tin, OSP, Benefits, Issues)
 - Tin Whisker

20. Cutting Edge Physics of Failure Methods and Models

- Work Approach to Obtaining a Physics of Failure Aging Law (Example: Creep, Wear)
- Using Free Energy Method to Assessing Life (Experimentally and Modeling)
- Generate an SN Curve using established rules (including notches, grain size, etc.)
- Weibull Beta to obtain physics of failure power aging laws
- Subtle Prognostics Using Noise (a subtle way to measure impending failure when obvious signs are not producing results)
- 1/f Noise in Oscillators and Other Devices - Reliability Considerations

21. Parametric Reliability

- Component Drift Analysis Methods & Sample Size Advantages

22. ESD Concepts

Advanced CDM

- Introduction CDM compared to HBM
- Why Ionizers can be important
- CDM Case Studies on Test Fixtures and Common ESD Problem
- Advanced Audits/Investigation, Test Fixtures
- Assessing ESD: Difficulty in Failure Analysis

ESD Protection Devices & Circuits

- ESD Test Circuits: Component vs. System Testing
- Protection Devices & Protection Circuits: Diodes, Varistors, Transistor Circuits, Discretes, Spark Gaps, PESD, L-R-C Passive Devices, and Mechanical Protection

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23. Putting it all Together